Unsupervised Anomaly Detection on metal surfaces after machining

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1. Introduction

Anomaly Detection is a common issue in Computer Vision, including e.g.: detection of defects during quality control in the manufacturing industry. Due to the highly unbalanced datasets (small number of samples with anomalies) and the lack of knowledge of all types of anomalies, the use of supervised learning is often suboptimal. In our research we used Unsupervised Anomaly Detection (UAD) methods, which are based on gaining knowledge during training model on anomaly-free-samples and checking this knowledge through evaluation on samples with and without anomalies, to solve these problems.

2. Problem definition

After the machining process, various defects (examples are presented in Fig. 1) can occur on the surface. Their vision inspection can be very useful for evaluating the machined surface as well as for designing adaptive machining controls. Due to the pre-optimized machining process, the probability of defects is quite low. The proposed methods for defects detection should, based on the learned patterns from anomaly-free samples (correct surface is characterized by periodical traces of the machining tool as presented in Fig. 1), detect samples with anomalies.

3. Goals

Development of method for defects detection on metal surfaces based on SOTA ML models in unsupervised anomaly detection and localization. Evaluation methods on three different detasets related to our problem:



Fig. 1 Examples of surface defects after machining (spalling-1, tear-2, build-up-3, crack-4).

4. Methods

- **SPADE** (Sub-Image Anomaly Detection with Deep Pyramid Correspondences)[1],
- Mahalanobis (Modeling the Distribution of Normal Data in Pre-Trained Deep Features for Anomaly Detection)[2],
- **DifferNet** (Semi-Supervised Defect Detection with Normalizing Flows)[3].

- Magnetic Tile Dataset (MTD)[4],
- MVTec Anomaly Detection Dataset (MVTec)[5],
- INTOR in-house dataset with anomalies on train wheelsets surface (INTOR).

5. Metrics for evaluation

Model Output: anomaly score for whole image (image level) or pixels (pixel level)

Metric: Area Under ROC Curve (AUC) based on calculated anomaly scores

6.4. Results - pixel segmentation

	Dataset		
Method	MTD	MVTec	INTOR
SPADE	0.855	0.854	0.918
Mahalanobis	0.937	0.947	0.951
DifferNet	0.964	0.949	0.948

6.1. Results - image level AUC

6.2. Results - pixel level AUC					
	Dataset				
Method	MTD	MVTec	INTOR		
SPADE	0.815	0.964	0.974		



7. Conclusions

- Our models achieved satisfactory results at image and pixel level on different datasets and can be successfully used to solve problem of anomalies detection on metal surfaces after machining,
- Segmentation of anomalies (Fig. 2) is relatively computationally costly, but increases significantly the level of explainability and comprehensibility of ML models,
- Preliminary assessment of the occurrence of anomalies at the image level (high AUC, low infer-



Fig. 3 Examples of anomaly segmentation for samples from different datasets with SPADE.

8. References

[1] N. Cohen and Y. Hoshen, "Sub-image anomaly detection with deep pyramid correspondences," *arXiv preprint arXiv:2005.02357*, 2020.

ence time) and subsequent segmentation at the pixel level if anomaly occurs can significantly increase the speed of inference compared to one-stage segmentation,

• Next step in our research will be defects clustering to discover the main types of defects occurring on metal surfaces after machining.

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[2] O. Rippel, P. Mertens, and D. Merhof, "Modeling the distribution of normal data in pre-trained deep features for anomaly detection," *arXiv preprint arXiv:2005.14140*, 2020.

- [3] M. Rudolph, B. Wandt, and B. Rosenhahn, "Same same but differnet: Semi-supervised defect detection with normalizing flows," *arXiv preprint arXiv:2008.12577*, 2020.
- [4] Y. Huang, C. Qiu, and K. Yuan, "Surface defect saliency of magnetic tile," *The Visual Computer*, vol. 36, no. 1, pp. 85–96, 2020.
- [5] P. Bergmann, M. Fauser, D. Sattlegger, and C. Steger, "Mvtec ad-a comprehensive real-world dataset for unsupervised anomaly detection," in *Proceedings* of the IEEE Conference on Computer Vision and Pattern Recognition, pp. 9592–9600, 2019.